

Search Notes 	Application/Control No. 10/817,553	Applicant(s)/Patent under Reexamination REED, DAVID G.
Examiner Christopher B. Shin	Art Unit 2181	

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
710	310,311,5	12/24/2006	CS
710	23,33,52	12/24/2006	CS
711	141,154	12/24/2006	CS
711/169		12/24/2006	CS

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
PLUS	6/8/2006	CS
PALM	6/8/2006	CS
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWNET, IBMTDB)	12/23/2006	CS